

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.5[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)**Quick Links**» [See](#)**Welcome to IEEE Xplore®**Your search matched **[0]** of **[988757]** documents.

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)

You may refine your search by editing the current search expression or entering a new one the text box. Then click search Again.

[Search Again](#)**OR**

Use your browser's back button to return to your original search page.

Results:

No documents matched your query.

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) | [Publications/Services](#) | [Standards](#) | [Conferences](#) | [Careers/Jobs](#)**IEEE Xplore**
RELEASE 1.5[Help](#) | [FAQ](#) | [Terms](#) | [IEEE Peer Review](#)[Quick Links](#)

Welcome to IEEE Xplore®

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

Print Format

Your search matched **1** of **988757** documents.A maximum of **1** results are displayed, **25** to a page, sorted by **Relevance** in **descending** order.You may refine your search by editing the current search expression or entering a new one the text box. Then click **Search Again**.

(decide or determine)<sentence> (lock <near/5> type)

Search Again**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 Determination of a factor of Fabry-Perot-type semiconductor laser by injection locking***van Exter, M.P.; Woerdman, J.P.;*

Electronics Letters, Volume: 28 Issue: 17, 13 Aug. 1992

Page(s): 1607 -1608

[\[Abstract\]](#) [\[PDF Full-Text \(192 KB\)\]](#) [IEEE JNL](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

IEEE HOME | SEARCH IEEE | SHOP | WEB ACCOUNT | CONTACT IEEE

[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.5[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)» [See](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library
- Print Format

Your search matched **2** of **990765** documents.A maximum of **2** results are displayed, **25** to a page, sorted by **Relevance** in **descending** order.

You may refine your search by editing the current search expression or entering a new one the text box.

Then click **Search Again**.

((decide <or> determine)<near/4> lock) <paragraph> (\$

Search Again**Results:**

Journal or Magazine = JNL Conference = CNF Standard = STD

1 A study of throughput degradation following single node failure in a d sharing system*Bowen, N.S.; Roy-Chowdhury, A.;*

Fault-Tolerant Computing, 1994. FTCS-24. Digest of Papers., Twenty-Fourth International Symposium on , 15-17 June 1994

Page(s): 310 -319

[\[Abstract\]](#) [\[PDF Full-Text \(736 KB\)\]](#) [IEEE CNF](#)**2 Evaluating the impact of the programming model on the performance complexity of software DSM systems***Seidel, C.B.; Bianchini, R.; Amorim, C.L.;*

Parallel Processing, 1999. Proceedings. 1999 International Conference on , 21-2 Sept. 1999

Page(s): 228 -236

[\[Abstract\]](#) [\[PDF Full-Text \(104 KB\)\]](#) [IEEE CNF](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved